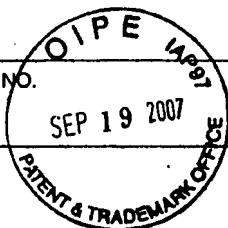


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		APPLICANT CHO et al.	
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CHO et al.

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